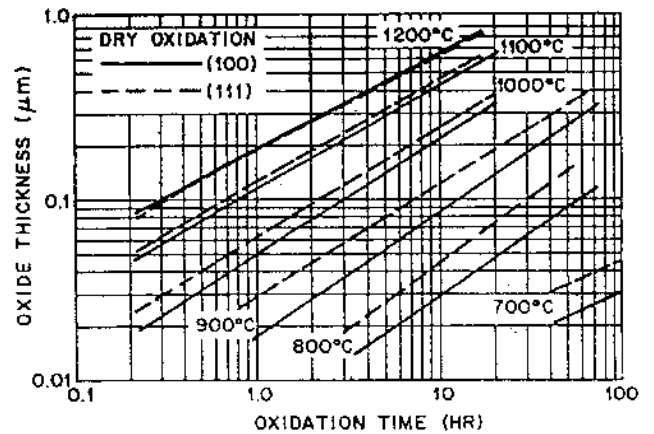
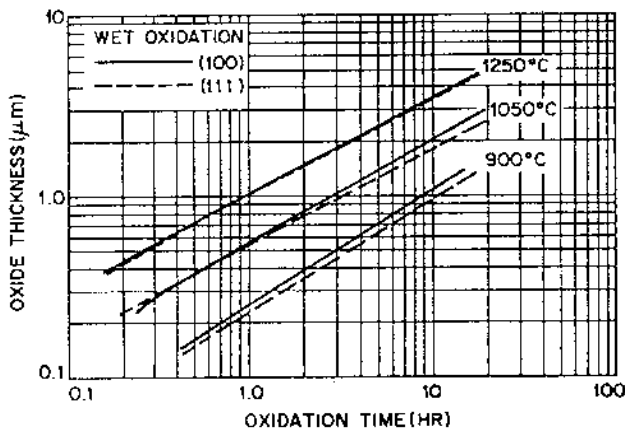


1. How long will it take to thermally grow a 1.0 μm thick SiO_2 film on a (100) substrate at 1200°C, by (a) wet oxidation, and (b) 0.2 μm dry and then 0.8 μm wet oxidation

How about growing a 2.0 μm thick wet SiO_2 at 1100°C



2. Can you estimate the residual stress of the SiO_2 film for problem 1, (a) after the substrate is brought outside the furnace ($T = 30^\circ\text{C}$)

Thermal expansion coefficients : $\text{Si} : 2.3 \times 10^{-6}/^\circ\text{C}$, and $\text{SiO}_2 : 5 \times 10^{-7}/^\circ\text{C}$

Young's modulus : $\text{SiO}_2 : 70 \text{ GPa}$

3. If the SiO_2 film in Prob. 2 is only grown on one side of the substrate, then the substrate will be deformed like I or II after brought outside the furnace and cooled down to room temperature, why?

